L Number		Search Text	DB	Time stamp
1	2799	250/341.8,306,307,559.3.ccls.	USPAT;	2003/10/22 15:11
	 - -		US-PGPUB;	1
			EPO; JPO;	
			IBM_TDB	
2	87	"critical dimension" AND 250/341.8,306,307,559.3.ccls.	USPAT;	2003/10/22 15:12
	i i		US-PGPUB;	İ
			EPO; JPO;	
ŀ			IBM_TDB	}
3	93	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4	USPAT;	2003/10/22 15:12
		nanometrology) AND 250/341.8,306,307,559.3.ccls.	US-PGPUB;	}
			EPO; JPO;	
			IBM_TDB	
-	0	scatterometry AND 250/237R.ccls.	USPAT;	2003/08/26 16:35
]			US-PGPUB;	
į			EPO; JPO;	
ļ			IBM_TDB	
-	205	scatterometry	USPAT;	2003/08/26 16:40
į į			US-PGPUB;	
			EPO; JPO;	1
			IBM_TDB	
-	963	profilometry	USPAT;	2003/08/26 16:40
j			US-PGPUB;	
i	· 		EPO; JPO;	
			IBM_TDB	1
-	0	250/237R.ccls. AND profilometry	USPAT;	2003/08/26 16:42
			US-PGPUB;]
			EPO; JPO;	Ì
Į	ı	! !	IBM_TDB	
-	8	(scatterometry OR profilometry) AND 356/614,616,620.ccls.	USPAT;	2003/09/03 13:27
İ		 	US-PGPUB;	
!			EPO, JPO,	
			IBM_TDB	
! -	8	(scatterometry OR profilometry OR reflectometry) AND	USPAT;	2003/09/03 14:09
		356/614,616,620.ccls.	US-PGPUB;	
l i			EPO; JPO;	
l			IBM_TDB	
-	4106	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4)	USPAT;	2003/10/07 11:28
		AND (pitch OR dimension)	US-PGPUB;	
Ì			EPO; JPO;	
			IBM_TDB	
i -	1	((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4)	USPAT;	2003/09/03 14:11
		AND (pitch OR dimension)) AND 250/237R.ccls.	US-PGPUB;	
			EPO; JPO;	
<u> </u>	204	OFO(0) and a ONIO ((alling a mode) 4 and a set of the s	IBM_TDB	0000/00/00 44:44
-	331	250/\$.ccls. AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	USPAT;	2003/09/03 14:11
		scatteromet\$4) AND (pitch OR dimension))	US-PGPUB;	į
			EPO; JPO;	
ļ	224	(water substrate (integrated AD Lairewith) AND (DEO/M and	IBM_TDB	1 2002/00/02 14:40
-	224	(wafer substrate (integrated ADJ circuit)) AND (250/\$.ccls.	USPAT;	2003/09/03 14:12
		AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	US-PGPUB;	
		scatteromet\$4) AND (pitch OR dimension)))	EPO; JPO;	į
_	1.40	(/wafer substrate (integrated AD Lairquit)) AND (250/6 and	IBM_TDB	2003/00/03 45:33
-	142	((wafer substrate (integrated ADJ circuit)) AND (250/\$.ccls. AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	USPAT;	2003/09/03 15:33
İ		, ,, ,	US-PGPUB;	
		scatteromet\$4) AND (pitch OR dimension)))) AND @pd<20020225	EPO; JPO;	
-	714		IBM_TDB	2003/00/03 15:32
	714	, , , , , , , , , , , , , , , , , , , ,	USPAT;	2003/09/03 15:32
		AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	US-PGPUB;	
		scatteromet\$4) AND (pitch OR dimension))	EPO; JPO;	i
	219	356/\$ cole AND //(determines measured) NEADA (notice)	IBM_TDB USPAT;	2003/09/03 15:33
- !	219	356/\$.ccls. AND (((determin\$5 measur\$4) NEAR4 (period	1	2003/09/03 10.33
		pitch dimension)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4) AND (pitch OR dimension)))	US-PGPUB; EPO; JPO;	
!		Promometer scatterometer) AND (pitch OR dimension)))	IBM TDB	
Search Histo	40/00/0	3 3:17:29 PM Page 1	T IDINITION	<u> </u>

Search History 10/22/03 3:17:29 PM Page 1

-	131	(356/\$.ccls. AND (((determin\$5 measur\$4) NEAR4 (period	USPAT;	2003/09/03 15:33
		pitch dimension)) AND ((ellipsomet\$4 reflectomet\$4	US-PGPUB;	
		profilomet\$4 scatteromet\$4) AND (pitch OR dimension))))	EPO; JPO;	
		AND @pd<20020225	IBM_TDB	
-	672	356/614,616,620.ccls.	USPAT;	2003/10/07 11:28
	İ		US-PGPUB;	:
			EPO; JPO;	
			IBM TDB	i
-	1144	250/237R.ccls.	USPAT:	2003/10/07 11:28
			US-PGPUB;	1
			EPO; JPO;	
	!		IBM TDB	
-	i 1	("6433878").PN.	USPAT;	2003/10/07 14:23
			US-PGPUB;	
			EPO; JPO;	
			IBM TDB	
_	9	("4870289" "5164790" "5413884" "5576829" "5879844"	USPAT	2003/10/07 14:23
		"5962173" "5963329" "6137570" "6187483").PN.	00.71.	2000,10,0,11,20
_	17	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4	USPAT:	2003/10/22 15:12
_	''	nanometrology) AND (356/614,616,620.ccls. 250/237R.ccls.)	US-PGPUB;	2000/10/22 10:12
		Hallottlettology) AND (330/014,010,020.0018. 230/20/11.0018.)	EPO; JPO;	
			IBM_TDB	
	8	((feature OR structure) WITH (dimension OR measurement	USPAT:	2003/10/09 17:15
-	•	OR pitch)) AND ((ellipsomet\$4 reflectomet\$4 profilomet\$4	,	2003/10/09 17.13
			US-PGPUB;	
		scatteromet\$4 nanometrology) AND (356/614,616,620.ccls.	EPO; JPO;	
		250/237R.ccls.))	IBM_TDB	2003/10/14 15:02
-	1	("6433878").PN.	USPAT;	2003/10/14 15.02
			US-PGPUB;	
	;		EPO; JPO;	
		(050/000 405 500 005 004 005 000 040) 001 0	IBM_TDB	0000/40/00 47:00
-	1735	(356/399,495,503,625,634,635,630,640).CCLS.	USPAT;	2003/10/20 17:39
			US-PGPUB;	j
			EPO; JPO;	
			IBM_TDB	0000/40/00 47 40
-	161	(ellipsomet\$4 reflectomet\$4 profilomet\$4 scatteromet\$4	USPAT;	2003/10/20 17:40
		nanometrology) AND	US-PGPUB;	
		((356/399,495,503,625,634,635,630,640).CCLS.)	EPO; JPO;	
			IBM_TDB	
-	9	("5867276" "5877880" "5880838" "6051348" "6081334"	USPAT	2003/10/21 13:00
		"6141107" "6245584" "6383888" "6423977").PN.		
-	11107	lintegrated circuit" AND pitch AND pattern	USPAT;	2003/10/21 15:13
			US-PGPUB;	
			EPO; JPO;	
			IBM_TDB	
-	43	scatterometry AND ("integrated circuit" AND pitch AND	USPAT;	2003/10/22 15:10
		pattern)	US-PGPUB;	
			EPO; JPO;	
	İ		IBM TDB	